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# **MOSFET** – Single N-Channel, SUPERFET<sup>®</sup> III, FRFET<sup>®</sup> **650 V, 75 A, 27.4 m** $\Omega$

# **NVH4L027N65S3F**

#### **Features**

- Ultra Low Gate Charge & Low Effective Output Capacitance
- Lower FOM (R<sub>DS(on) max.</sub> x Q<sub>g typ.</sub> & R<sub>DS(on) max.</sub> x E<sub>OSS</sub>)
- AEC-Q101 Qualified and PPAP Capable
- These Devices are Pb-Free and are RoHS Compliant

#### MAXIMUM RATINGS (T<sub>C</sub> = 25°C unless otherwise noted)

Parameter	Symbol	Value	Unit
Drain-to-Source Voltage	$V_{DSS}$	650	٧
Gate-to-Source Voltage - DC	$V_{GSS}$	±30	V
Gate-to-Source Voltage - AC (f > 1 Hz)	$V_{GSS}$	±30	V
Drain Current – Continuous (T <sub>C</sub> = 25°C)	I <sub>D</sub>	75	Α
Drain Current – Continuous (T <sub>C</sub> = 100°C)	I <sub>D</sub>	60	Α
Drain Current – Pulsed (Note 3)	I <sub>DM</sub>	187.5	Α
Power Dissipation $(T_C = 25^{\circ}C)$	$P_{D}$	595	W
Power Dissipation – Derate Above 25°C	$P_{D}$	4.76	W/°C
Operating Junction and Storage Temperature Range	T <sub>J</sub> , T <sub>STG</sub>	-55 to +150	°C
Single Pulsed Avalanche Energy (Note 4)	E <sub>AS</sub>	1610	mJ
Repetitive Avalanche Energy (Note 3)	E <sub>AR</sub>	5.95	mJ
MOSFET dv/dt	dv/dt	100	V/ns
Peak Diode Recovery dv/dt (Note 5)	dv/dt	50	V/ns
Max. Lead Temperature for Soldering Purposes (1/8" from case for 5 s)	T <sub>L</sub>	300	°C

#### THERMAL CHARACTERISTICS

Parameter	Symbol	Value	Unit
Thermal Resistance, Junction-to-Case, Max. (Notes 1, 2)	$R_{\theta JC}$	0.21	°C/W
Thermal Resistance, Junction-to-Ambient, Max. (Notes 1, 2)	$R_{\theta JA}$	40	

Stresses exceeding those listed in the Maximum Ratings table may damage the device. If any of these limits are exceeded, device functionality should not be assumed, damage may occur and reliability may be affected.

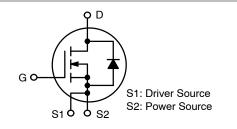
- 1. The entire application environment impacts the thermal resistance values shown. They are not constants and are only valid for the particular conditions noted.
- 2. Assembled to an infinite heatsink with perfect heat transfer from the case (assumes 0 K/W thermal interface).
- 3. Repetitive rating: pulse-width limited by maximum junction temperature.
- 4.  $I_{AS}$  = 15 A,  $R_{G}$  = 25  $\Omega$ , starting  $T_{J}$  = 25°C. 5.  $I_{SD}$  ≤ 37.5 A, di/dt ≤ 200 A/ $\mu$ s,  $V_{DD}$  ≤ 400 V, starting  $T_{J}$  = 25°C.



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V <sub>DSS</sub>	R <sub>DS(ON)</sub> MAX	I <sub>D</sub> MAX
650 V	27.4 mΩ @ 10 V	75 A



#### **POWER MOSFET**

TO-247-4LD CASE 340CJ



**MARKING** 

= ON Semiconductor Logo
= Assembly Plant Code
= Data Code (Year & Week)

= Lot

\$Y &Z &3

NVH4L027N65S3F = Specific Device Code

#### ORDERING INFORMATION

Device	Package	Shipping
NVH4L027N65S3F	TO-247-4LD (Pb-Free)	30 Units / Tube

### **ELECTRICAL CHARACTERISTICS** ( $T_C = 25^{\circ}C$ unless otherwise noted)

Parameter	Symbol	Test Conditions	Min	Тур	Max	Unit
OFF CHARACTERISTICS					•	•
Drain-to-Source Breakdown Voltage	BV <sub>DSS</sub>	$V_{GS} = 0 \text{ V}, I_D = 1 \text{ mA}, T_J = 25^{\circ}\text{C}$	650			V
Drain-to-Source Breakdown Voltage	BV <sub>DSS</sub>	V <sub>GS</sub> = 0 V, I <sub>D</sub> = 10 mA, T <sub>J</sub> = 150°C	700			V
Breakdown Voltage Temperature Coefficient	$\Delta BV_{DSS}/ \Delta T_{J}$	I <sub>D</sub> = 20 mA, Referenced to 25°C		610		mV/°C
Zero Gate Voltage Drain Current	I <sub>DSS</sub>	V <sub>GS</sub> = 0 V, V <sub>DS</sub> = 650 V			10	μΑ
		V <sub>DS</sub> = 520 V, T <sub>C</sub> = 125°C		590		
Gate-to-Body Leakage Current	I <sub>GSS</sub>	$V_{GS} = \pm 30 \text{ V}, V_{DS} = 0 \text{ V}$			±100	nA
ON CHARACTERISTICS				-		•
Gate Threshold Voltage	V <sub>GS(th)</sub>	$V_{GS} = V_{DS}$ , $I_D = 3 \text{ mA}$	3.0		5.0	V
Threshold Temperature Coefficient	$\Delta V_{GS(th)}/\Delta T_{J}$	$V_{GS} = V_{DS}$ , $I_D = 3 \text{ mA}$		-7.3		mV/°C
Static Drain-to-Source On Resistance	R <sub>DS(on)</sub>	V <sub>GS</sub> = 10 V, I <sub>D</sub> = 35 A		21.5	27.4	mΩ
Forward Transconductance	9FS	V <sub>DS</sub> = 20 V, I <sub>D</sub> = 37.5 A		57		S
DYNAMIC CHARACTERISTICS					!	!
Input Capacitance	C <sub>iss</sub>			7780		pF
Output Capacitance	C <sub>oss</sub>	V <sub>GS</sub> = 0 V, V <sub>DS</sub> = 400 V, f = 1 MHz		200		
Reverse Transfer Capacitance	C <sub>rss</sub>			26		
Effective Output Capacitance	C <sub>oss(eff.)</sub>	V <sub>DS</sub> = 0 V to 400 V, V <sub>GS</sub> = 0 V		1880		pF
Energy Related Output Capacitance	C <sub>oss(er.)</sub>	V <sub>DS</sub> = 0 V to 400 V, V <sub>GS</sub> = 0 V		347		pF
Total Gate Charge at 10 V	Q <sub>G(TOT)</sub>			227		nC
Threshold Gate Charge	Q <sub>G(TH)</sub>	V <sub>GS</sub> = 10 V, V <sub>DS</sub> = 400 V, I <sub>D</sub> = 37.5 A		35		=
Gate-to-Source Gate Charge	Q <sub>GS</sub>	(Note 6)		67		
Gate-to-Drain "Miller" Charge	Q <sub>GD</sub>			87		=
Equivalent Series Resistance	ESR	f = 1 MHz		2.2		Ω
SWITCHING CHARACTERISTICS				1	I.	1
Turn-On Delay Time	t <sub>d(on)</sub>			42		ns
Turn-On Rise Time	t <sub>r</sub>	$V_{GS} = 10 \text{ V}, V_{DD} = 400 \text{ V},$		34		ns
Turn-Off Delay Time	t <sub>d(off)</sub>	$I_D = 37.5 \text{ A}, R_g = 2 \Omega$ (Note 6)		153		ns
Turn-Off Fall Time	t <sub>f</sub>	,		18		ns
SOURCE-DRAIN DIODE CHARACTER	ISTICS			1	I.	1
Maximum Continuous Source-to- Drain Diode Forward Current	I <sub>S</sub>	V <sub>GS</sub> = 0 V			75	Α
Maximum Pulsed Source-to-Drain Diode Forward Current	I <sub>SM</sub>	V <sub>GS</sub> = 0 V			187.5	Α
Source-to-Drain Diode Forward Voltage	$V_{SD}$	V <sub>GS</sub> = 0 V, I <sub>SD</sub> = 37.5 A			1.3	V
Reverse Recovery Time	t <sub>rr</sub>			171		ns
Charge Time	ta	V <sub>GS</sub> = 0 V, dI <sub>F</sub> /dt = 100 A/μs,		141		1
Discharge Time	t <sub>b</sub>	$I_{SD} = 37.5 \text{ A}$		29		1
Reverse Recovery Charge	Q <sub>rr</sub>			973		nC

Product parametric performance is indicated in the Electrical Characteristics for the listed test conditions, unless otherwise noted. Product performance may not be indicated by the Electrical Characteristics if operated under different conditions.

6. Essentially independent of operating temperature typical characteristics.

#### **TYPICAL CHARACTERISTICS**

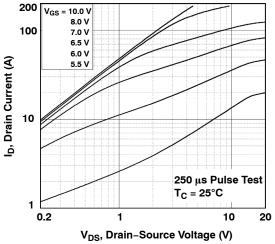


Figure 1. On-Region Characteristics

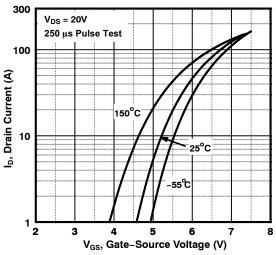


Figure 3. Transfer Characteristics

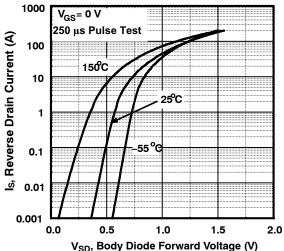


Figure 5. Body Diode Forward Voltage Variation vs. Source Current and Temperature

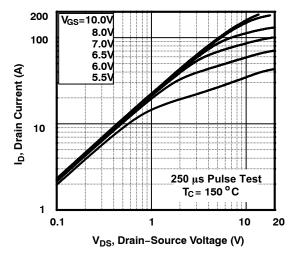


Figure 2. On-Region Characteristics

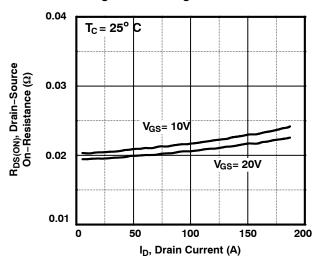


Figure 4. On-Resistance Variation vs. Drain Current and Gate Voltage

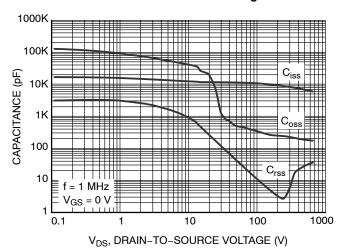


Figure 6. Capacitance Characteristics

#### **TYPICAL CHARACTERISTICS**

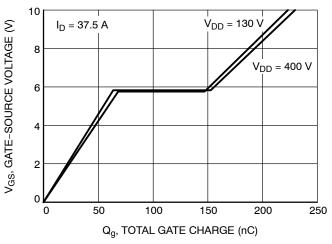


Figure 7. Gate Charge Characteristics

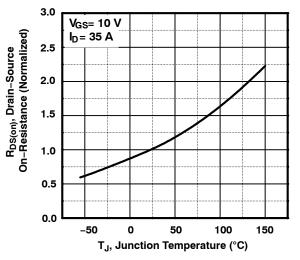
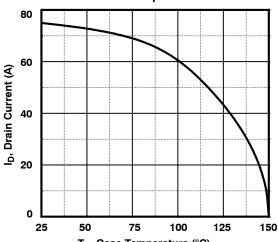


Figure 9. On-Resistance Variation vs. Temperature



T<sub>C</sub>, Case Temperature (°C)
Figure 11. Maximum Drain Current vs. Case
Temperature

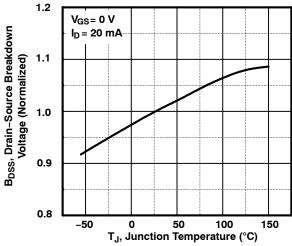


Figure 8. Breakdown Voltage Variation vs. Temperature

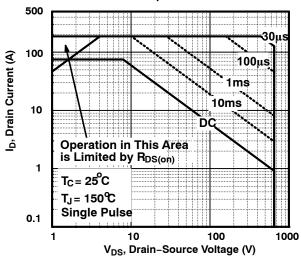
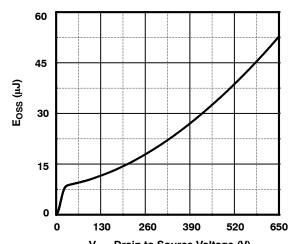


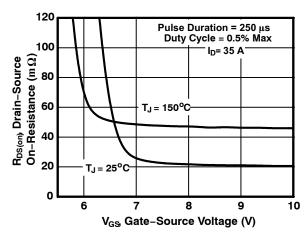
Figure 10. Maximum Safe Operating Area



V<sub>DS</sub>, Drain to Source Voltage (V)
Figure 12. EOSS vs. Drain-to-Source Voltage

#### **TYPICAL CHARACTERISTICS**

1.2



Normalized Gate

Threshold Voltage

8.0

0.4

-50

0 50

10

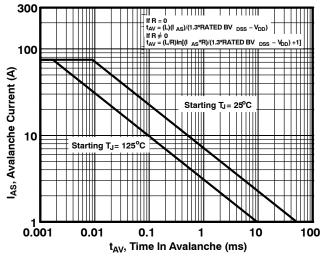
Figure 13. RDSON vs. Gate Voltage

Figure 14. Normalized Gate Threshold Voltage vs. Temperature

T<sub>J</sub>, Junction Temperature (°C)

 $V_{GS} = V_{DS}$  $I_{D} = 3 \text{ mA}$ 

150



NOTE: Refer to Fairchild Application Notes AN7514 and AN7515

Figure 15. Unclamped Inductive Switching Capability

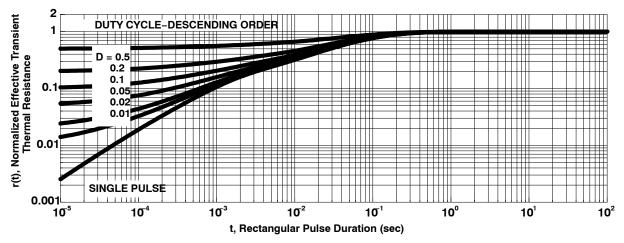


Figure 16. Transient Thermal Response Curve

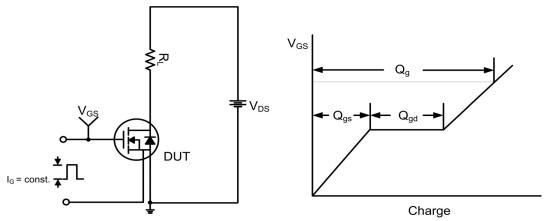


Figure 17. Gate Charge Test Circuit & Waveform

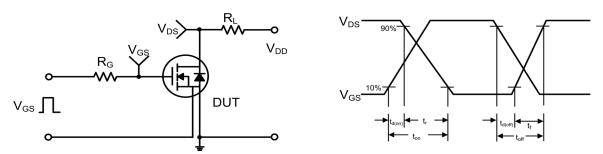


Figure 18. Resistive Switching Test Circuit & Waveforms

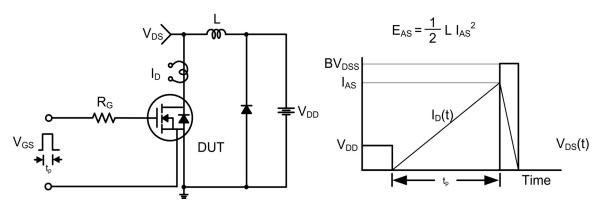


Figure 19. Unclamped Inductive Switching Test Circuit & Waveforms

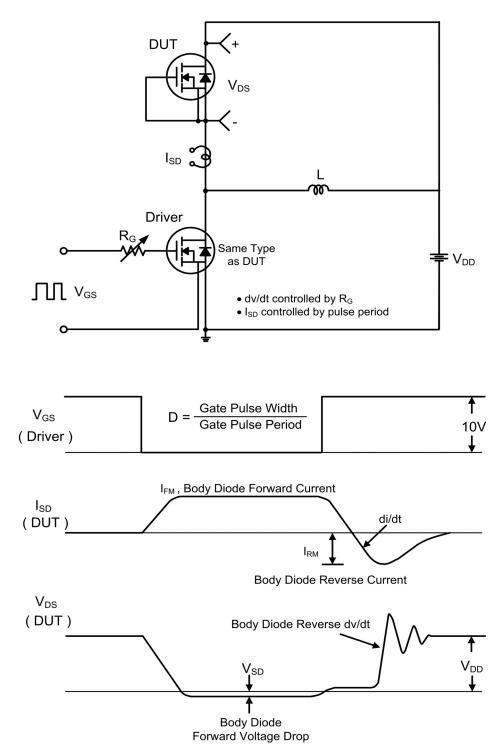
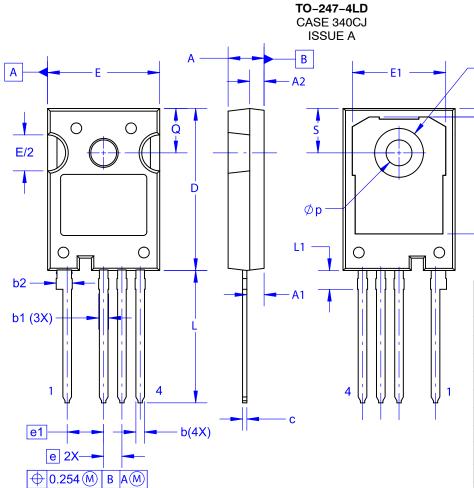


Figure 20. Peak Diode Recovery dv/dt Test Circuit & Waveforms

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DIM	MILLIMETERS		
DIM	MIN	NOM	MAX
Α	4.80	5.00	5.20
A1	2.10	2.40	2.70
A2	1.80	2.00	2.20
b	1.07	1.20	1.33
b1	1.20	1.40	1.60
b2	2.02	2.22	2.42
С	0.50	0.60	0.70
D	22.34	22.54	22.74
D1	16.00	16.25	16.50
D2	0.97	1.17	1.37
е	2.54 BSC		
e1	5.08 BSC		
E	15.40	15.60	15.80
E1	12.80	13.00	13.20
E/2	4.80	5.00	5.20
L	18.22	18.42	18.62
L1	2.42	2.62	2.82
р	3.40	3.60	3.80
p1	6.60	6.80	7.00
Q	5.97	6.17	6.37
S	5.97	6.17	6.37

Øp1

D1

D2

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